

Notice of References Cited	Application/Control No. 10/605,355	Applicant(s)/Patent Under Reexamination SHIH ET AL.	
	Examiner Cheukfan Lee	Art Unit 2625	Page 1 of 1

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*	B	US-2005/0062864 A1	03-2005	Mabuchi, Keiji	348/294
*	C	US-2007/0120989 A1	05-2007	Minami et al.	348/266
*	D	US-7,088,279	08-2006	Muramatsu et al.	341/155
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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